Se	Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/836,006	WANG ET AL.	
Examiner	Art Unit	
Sunray Chang	2121	

SEARCHED				
Class	Subclass	Date	Examiner	
709	231	3/2/2005	sc	
375	240.1	3/2/2005	sc	
375	240.12	3/2/2005	sc	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
709	231	3/2/2005	sc	
375	240.1	3/2/2005	sc	
375	240.12	3/2/2005	sc	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST (USPAT, US_PGPUB, JPO, EPO, DERWENT, IBM_TDB)	3/2/2005	sc	
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